

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/798,119	<b>Applicant(s)/Patent under Reexamination</b> CHUNG, YIH-LIN
<b>Examiner</b> Alicia R. Hughes	<b>Art Unit</b> 1614	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner